

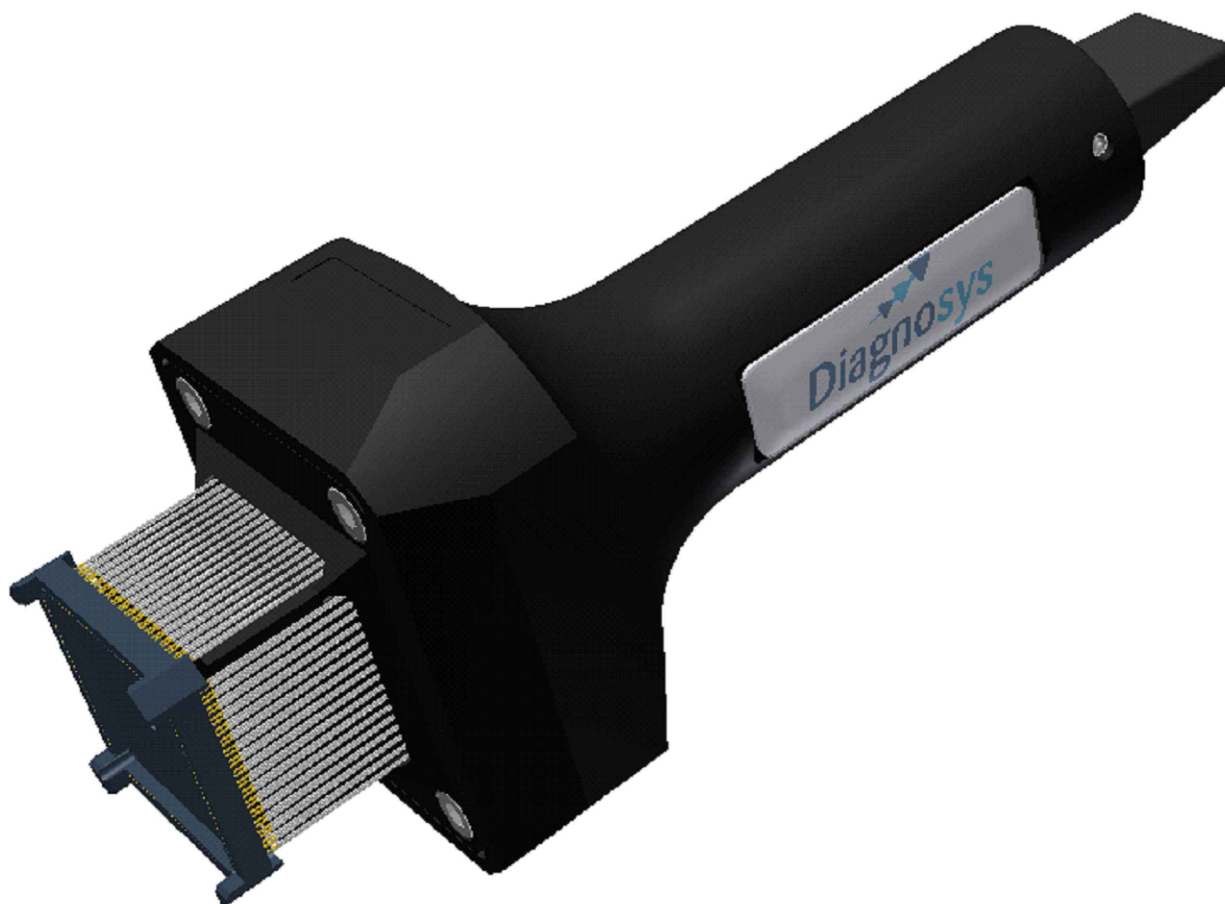
## Introduction

This Test Interface is a hand held test clip, designed to probe simultaneously the leads of an assembled IC. Terminated with six 25 way male "D" type connectors, the interface makes temporary electrical contact with the leads of the device, in a two step action:

- the interface is positioned over the device to be tested (Lining it up with the body of the device and the leads).
- by pushing the handle further, the high-performance microprobes will reach the leads of the device and make electrical contact.

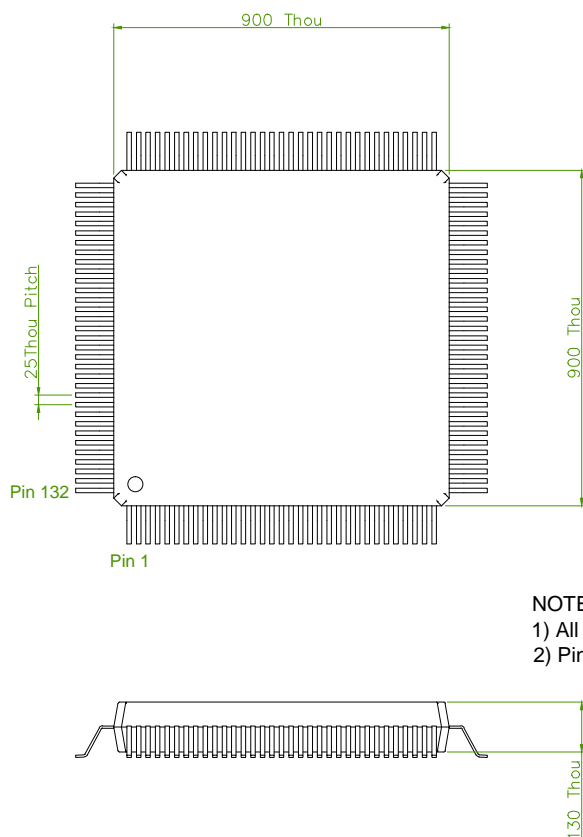
## Features

- achieves the best combination of reliability, repeatability, serviceability and user-friendliness;
- high contact pressure at probe tip, for repeatable and reliable contact;
- high reliability and long life interchangeable microprobes;
- sweeping action gold plated contacts, for reliable contact and low ohmic resistance of interconnections;
- high current rating (for single channel, in ambient air with 70°F [20°C]) : 1.5A
- impact, solvent and temperature resistant plastics, with low friction;
- wide range of operating temperatures (commercial): [0°C to +70°C]
- clear markings on the body, indicating Pin 1 of IC being tested, to prevent probing the wrong way round;
- packaged in a hard wearing, high resistance to damage Polypropylene case with foam insets, the Test Interface can withstand high impact in transit.
- case can be used for safe storage when the Test Interface is not in use, and subsequent transport.
- very flexible cable (military quality harnessing) with low friction, high performance TFE TEFLON insulated wires (MIL-W-16878E Type E, UL1213);



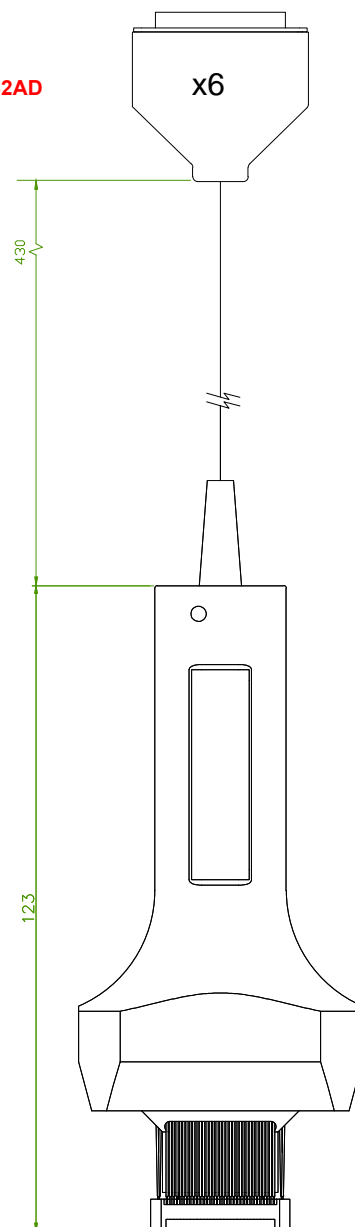
## Specification

- It will accommodate a 132Pin (C)QFP, 25Thou Pitch, LxWxH: 900Thou x 900Thou x 130Thou; **JEDEC M0-082AD**
- Maximum number of interconnections (channels): 132
- Current rating, with all contacts loaded (maximum continuous current, non inductive): 0.5A /channel;
- Contact resistance (average): 80 mΩ /channel;
- Insulation resistance: 5MΩ Min.
- Volume resistivity of plastic parts:  $10^{15}$  Ω-cm @ 50%RH.
- Fatigue life of probes: Min. 1,000,000 cycles at normal working distance;
- Working distance (normal stroke): 1.3mm;
- Microprobe force at point of contact (normal stroke): 0.3N



### NOTES

- 1) All dimensions in mm, unless otherwise specified.
- 2) Pin 1 of IC marked in red on probe body.



## Connections Table

IC Pin	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32	33
Channel	50	46	72	42	23	47	21	43	17	40	20	39	22	38	18	48	13	36	10	35	4	30	8	31	9	27	5	37	1	34	54	28	59

IC Pin	34	35	36	37	38	39	40	41	42	43	44	45	46	47	48	49	50	51	52	53	54	55	56	57	58	59	60	61	62	63	64	65	66
Channel	55	33	29	32	25	51	3	52	7	56	6	57	11	53	12	49	2	75	130	77	124	78	128	73	129	83	125	84	99	107	103	102	80

IC Pin	67	68	69	70	71	72	73	74	75	76	77	78	79	80	81	82	83	84	85	86	87	88	89	90	91	92	93	94	95	96	97	98	99
Channel	82	108	76	98	121	120	123	97	127	101	126	105	131	100	132	106	122	109	144	114	134	118	135	116	136	113	139	117	143	110	90	111	85

IC Pin	100	101	102	103	104	105	106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	121	122	123	124	125	126	127	128	129	130	131	132
Channel	94	112	119	74	115	96	141	86	137	87	140	88	142	91	138	95	133	69	24	65	14	68	15	70	16	66	19	61	44	58	45	41	62

## Maintenance

The Test Interface Head is maintenance free. The microprobes are self-cleaning. Immersion in water or contact between microprobes and any liquids should be avoided, as this could severely reduce the working life of microprobes.

Contamination is the primary cause of probe contact problems. This is generally caused by flux left as a residue on circuit boards. Other probe contaminants such as dust, fluff, oil and grime can also cause problems in other areas. Light brushing of the tips of the probes with nylon, bristle or soft metal brushes will dislodge most contaminants.